CURRICULUM VITAE

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RASHMI SAINI

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Educational Qualifications

Ph.D.	Indian Institute of Technology, Roorkee	Pursuing
M. Tech	National Institute of Technical Teachers' Training and Research (NITTTR) Chandigarh	2013
B. Tech	Guru Tegh Bahadur Institute of Technology, Delhi	2003

Details of Employment

Designation	Institute	from	to
Lecturer	College of engineering Roorkee	April 2005	July 2005
Assistant Professor	G.B.Pant Engineering College Pauri Garhwal	July 2005	presently working

Area of Interest

Image processing, Computer networks, Remote sensing, supervised image classifications, Machine learning, Ensemble classifiers.

Research Papers

[1] Saini, R., Dutta M., Kumar, R., A Comparative Study of Several Image Segmentation Techniques, Journal of Information and Operations Management, Volume 3, pp.21-24, 2012.

[2] Saini R., Image Segmentation for Uneven Lighting Images using Adaptive Thresholding and Dynamic Window based on Incremental Window Growing Approach, International Journal of compute application, Volume 56 – No 13, 2012.

[3] Saini, R., Dutta M., Document Image Binarization Techniques, Development and related Issues: A Review, International Journal of compute application, volume, 116(7), 2015.

[4] Saini R., Image Segmentation for Uneven Lighting Images based on Initial Window Size Selection, International Journal of compute application, Volume 156 – No 1, 2016.

[5] Saini, R. and Ghosh, S. K., Ensemble classifiers in remote sensing: A review, International Conference on Computing, Communication and Automation (ICCCA), pp. 1148-1152, 5-6 May 2017, Greater Noida. https://doi.org/10.1109/CCAA.2017.8229969

[6] Saini, R. and Ghosh, S. K., Exploring Capabilities of Sentinel-2 for Vegetation Mapping Using Random Forest. International Archives of the Photogrammetry, Remote Sensing and Spatial Information Sciences, Volume XLII-3, ISPRS TC III Mid-term Symposium "Developments, Technologies and Applications in Remote Sensing", pp. 1499-1502, 7–10 May, 2018, Beijing, China. DOI: 10.5194/isprs-archives-XLII-3-1499-2018.